# Si/SiC Hybrid Module – EliteSiC, I-Type NPC 1000 V, 400 A IGBT, 1200 V, 100 A SiC Diode, Q2 Package

# NXH400N100H4Q2F2PG, NXH400N100H4Q2F2SG, NXH400N100H4Q2F2SG-R

This high-denity, integrated power module combines high-performance IGBTs with rugged anti-parallel diodes.

#### **Features**

- Extremely Efficient Trench with Field Stop Technology
- Low Switching Loss Reduces System Power Dissipation
- Module Design Offers High Power Density
- Low Inductive Layout
- Low Package Height
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

### **Typical Applications**

- Solar Inverters
- Uninterruptable Power Supplies Systems

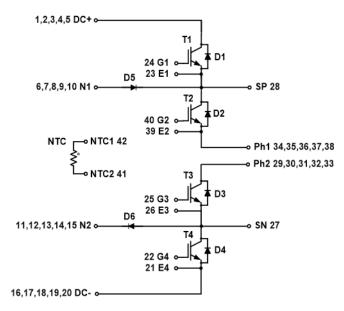
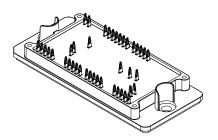
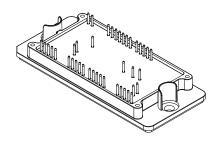


Figure 1. NXH400N100H4Q2F2PG/SG/SG-R Schematic Diagram

1



Q2PACK INPC PRESS FIT PINS PIM42, 93x47 (PRESSFIT) CASE 180BH



Q2PACK INPC SOLDER PINS PIM44, 93x47 (SOLDER PIN) CASE 180BS

#### **MARKING DIAGRAM**



NXH400N100H4Q2F2PG/SG = Specific Device Code
G = Pb-Free Package
AT = Assembly & Test Site
Code

YYWW = Year and Work Week
Code

#### PIN CONNECTIONS

See details pin connections on page 2 of this data sheet.

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 6 of this data sheet.

### **PIN CONNECTIONS**

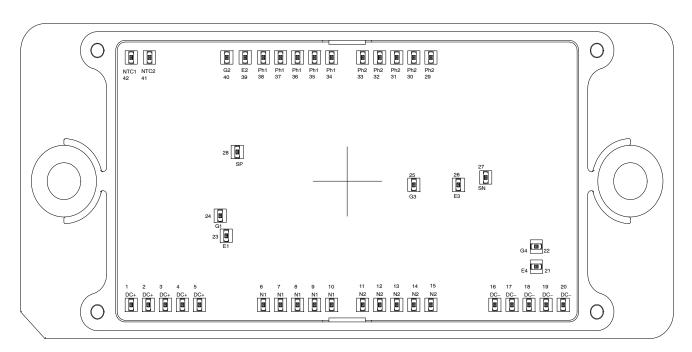


Figure 2. Pin Connections

### **ABSOLUTE MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Rating	Symbol	Value	Unit
OUTER IGBT (T1, T4)			•
Collector-Emitter Voltage	V <sub>CES</sub>	1000	V
Gate-Emitter Voltage Positive Transient Gate-Emitter Voltage ( $T_{pulse}$ = 5 $\mu$ s, D < 0.10)	V <sub>GE</sub>	±20 30	V
Continuous Collector Current @ T <sub>C</sub> = 80°C	I <sub>C</sub>	409	А
Pulsed Peak Collector Current @ T <sub>C</sub> = 80°C (T <sub>J</sub> = 150°C)	I <sub>C(Pulse)</sub>	1227	А
Maximum Power Dissipation (T <sub>J</sub> = 150°C)	P <sub>tot</sub>	959	W
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	175	°C
NNER IGBT (T2, T3)			
Collector-Emitter Voltage	V <sub>CES</sub>	1000	V
Gate-Emitter Voltage Positive Transient Gate-Emitter Voltage ( $T_{pulse}$ = 5 $\mu$ s, D < 0.10)	V <sub>GE</sub>	±20 30	V
Continuous Collector Current @ T <sub>C</sub> = 80°C	I <sub>C</sub>	360	А
Pulsed Peak Collector Current @ T <sub>C</sub> = 80°C (T <sub>J</sub> = 150°C)	I <sub>C(Pulse)</sub>	1080	А
Maximum Power Dissipation (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	805	W
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	175	°C
GBT INVERSE DIODE (D1, D2, D3, D4)			
Peak Repetitive Reverse Voltage	V <sub>RRM</sub>	1000	V
Continuous Forward Current @ T <sub>C</sub> = 80°C	I <sub>F</sub>	192	А
Repetitive Peak Forward Current (T <sub>J</sub> = 175°C)	I <sub>FRM</sub>	576	А

### ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

Rating	Symbol	Value	Unit	
IGBT INVERSE DIODE (D1, D2, D3, D4)				
Maximum Power Dissipation (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	482	W	
Minimum Operating Junction Temperature	$T_{JMIN}$	-40	°C	
Maximum Operating Junction Temperature	T <sub>JMAX</sub>	175	°C	
NEUTRAL POINT DIODE (D5, D6)				
Peak Repetitive Reverse Voltage	$V_{RRM}$	1200	V	
Continuous Forward Current @ T <sub>C</sub> = 80°C	I <sub>F</sub>	140	А	
Repetitive Peak Forward Current (T <sub>J</sub> = 175°C)	I <sub>FRM</sub>	420	А	
Maximum Power Dissipation (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	401	W	
Minimum Operating Junction Temperature	$T_{JMIN}$	-40	°C	
Maximum Operating Junction Temperature	$T_JMAX$	175	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL AND INSULATION PROPERTIES (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
THERMAL PROPERTIES			
Operating Temperature under Switching Condition	T <sub>VJOP</sub>	-40 to 150	°C
Storage Temperature Range	T <sub>stg</sub>	-40 to 125	°C
INSULATION PROPERTIES			
Isolation Test Voltage, t = 2 s, 50 Hz (Note 3)	V <sub>is</sub>	4000	$V_{RMS}$
Creepage Distance		12.7	mm
Comparative Tracking Index	CTI	>600	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

<sup>1.</sup> Refer to ELECTRICAL CHARACTERISTICS and/or APPLICATION INFORMATION for Safe Operating parameters.

<sup>2.</sup> Refer to ELECTRICAL CHĂRACTERISTICS and/or ÁPPLICATION INFORMATION for Safe Operating parameters.

<sup>3. 4000</sup> VA $\overline{C_{\text{RMS}}}$  for 1 second duration is equivalent to 3333 VAC $_{\text{RMS}}$  for 1 minute duration.

**ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$  unless otherwise specified)

Characteristic	Test Conditions	Symbol	Min	Тур	Max	Unit
OUTER IGBT (T1, T4) CHARACTER	ISTICS					
Collector-Emitter Cutoff Current	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1000 V	I <sub>CES</sub>	_	_	500	μА
Collector-Emitter Saturation Voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 400 A, T <sub>J</sub> = 25°C	V <sub>CE(sat)</sub>	_	1.77	2.3	V
	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 400 A, T <sub>J</sub> = 150°C	1	_	2.11	-	
Gate-Emitter Threshold Voltage	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 400 mA	V <sub>GE(TH)</sub>	4.1	5.1	6.1	V
Gate Leakage Current	V <sub>GE</sub> = ±20 V, V <sub>CE</sub> = 0 V	I <sub>GES</sub>	_	-	±2000	nA
Internal Gate Resistor		$R_{G}$	-	1.44	-	Ω
Turn-on Delay Time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	_	151	_	ns
Rise Time	$V_{CE}$ = 600 V, $I_{C}$ = 150 A $V_{GE}$ = -8 V, 15 V, $R_{Gon}$ = 6 Ω,	t <sub>r</sub>	_	35	_	
Turn-off Delay Time	$R_{Goff} = 11 \Omega$	t <sub>d(off)</sub>	_	551	_	
Fall Time	1	t <sub>f</sub>	-	68	-	
Turn-on Switching Loss per Pulse	1	E <sub>on</sub>	_	3270	_	μJ
Turn-off Switching Loss per Pulse	1	E <sub>off</sub>	_	5100	_	
Turn-on Delay Time	T <sub>J</sub> = 125°C	t <sub>d(on)</sub>	_	146	_	ns
Rise Time	$V_{CE}$ = 600 V, $I_{C}$ = 150 A $V_{GE}$ = -8 V, 15 V, $R_{Gon}$ = 6 Ω,	t <sub>r</sub>	_	40	-	
Turn-off Delay Time	$R_{Goff} = 11 \Omega$	t <sub>d(off)</sub>	_	626	_	
Fall Time	1	t <sub>f</sub>	_	88	-	
Turn-on Switching Loss per Pulse	1	E <sub>on</sub>	_	4165	_	μJ
Turn-off Switching Loss per Pulse	1	E <sub>off</sub>	_	8420	-	
Input Capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>ies</sub>	_	26093	-	pF
Output Capacitance	1	C <sub>oes</sub>	_	1012	-	1
Reverse Transfer Capacitance	1	C <sub>res</sub>	_	104	-	
Total Gate Charge	$V_{CE} = 600 \text{ V}, I_{C} = 300 \text{ A}, V_{GE} = -15 \text{ V} \sim 15 \text{ V}$	$Q_g$	-	1304	-	nC
Thermal Resistance – Chip-to-Heatsink	Thermal grease, Thickness = 2.1 Mil ±2%	R <sub>thJH</sub>	-	0.181	-	K/W
Thermal Resistance - Chip-to-Case	$\lambda = 2.9 \text{ W/mK}$	R <sub>thJC</sub>	-	0.073	-	K/W
NEUTRAL POINT DIODE (D5, D6) C	HARACTERISTICS	•		•		
Diode Forward Voltage	I <sub>F</sub> = 100 A, T <sub>J</sub> = 25°C	$V_{F}$	-	1.50	1.85	V
	I <sub>F</sub> = 100 A, T <sub>J</sub> = 150°C	†	-	2.07	-	
Reverse Recovery Time	T <sub>J</sub> = 25°C	t <sub>rr</sub>	-	19	-	ns
Reverse Recovery Charge	$V_{CE} = 600 \text{ V, } I_{C} = 150 \text{ A}$ $V_{GE} = -8 \text{ V, } 15 \text{ V, } R_{G} = 6 \Omega$	Q <sub>rr</sub>	-	229	-	nC
Peak Reverse Recovery Current	- VGE - 0 V, 10 V, 11G - 0 11	I <sub>RRM</sub>	_	19	-	Α
Peak Rate of Fall of Recovery Current	1	di/dt	_	6053	-	A/μs
Reverse Recovery Energy	1	E <sub>rr</sub>	-	164	-	μJ
Reverse Recovery Time	T <sub>J</sub> = 125°C	t <sub>rr</sub>	_	34	-	ns
Reverse Recovery Charge	$V_{CE} = 600 \text{ V, } I_{C} = 150 \text{ A}$ $V_{GF} = -8 \text{ V, } 15 \text{ V, } R_{G} = 6 \Omega$	Q <sub>rr</sub>	_	359	-	nC
Peak Reverse Recovery Current	_ GE - 1, 70 1, 1.G 0 22	I <sub>RRM</sub>	_	17	-	Α
Peak Rate of Fall of Recovery Current	1	di/dt	_	4621	_	A/μs
Reverse Recovery Energy	1	E <sub>rr</sub>	_	211	-	μJ
Thermal Resistance – Chip-to-Heatsink	Thermal grease, Thickness = 2.1 Mil ±2%	R <sub>thJH</sub>	=	0.364	=	K/W
Thermal Resistance - Chip-to-Case	λ = 2.9 W/mK	R <sub>thJC</sub>	_	0.237	_	K/W

**ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified) (continued)

Characteristic	Test Conditions	Symbol	Min	Тур	Max	Unit
INNER IGBT (T2, T3) CHARACTERIS	STICS					
Collector-Emitter Cutoff Current	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1000 V	I <sub>CES</sub>	=	=	500	μΑ
Collector-Emitter Saturation Voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 400 A, T <sub>J</sub> = 25°C	V <sub>CE(sat)</sub>	=	1.77	2.3	V
	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 400 A, T <sub>J</sub> = 150°C	1	_	2.11	-	
Gate-Emitter Threshold Voltage	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 400 mA	V <sub>GE(TH)</sub>	4.1	5.1	6.1	V
Gate Leakage Current	$V_{GE} = \pm 20 \text{ V}, V_{CE} = 0 \text{ V}$	I <sub>GES</sub>	_	-	±2000	nA
Internal Gate Resistor		$R_{G}$	-	1.44	-	Ω
Turn-on Delay Time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	=	149	-	ns
Rise Time	$V_{CE}$ = 600 V, $I_{C}$ = 150 A $V_{GE}$ = -8 V, 15 V, $R_{Gon}$ = 6 Ω,	t <sub>r</sub>	_	37	_	
Turn-off Delay Time	$R_{Goff} = 23 \Omega$	t <sub>d(off)</sub>	-	882	-	
Fall Time	1	t <sub>f</sub>	_	35	_	
Turn-on Switching Loss per Pulse	1	E <sub>on</sub>	_	4970	-	μJ
Turn-off Switching Loss per Pulse	1	E <sub>off</sub>	_	6010	_	
Turn-on Delay Time	T <sub>J</sub> = 125°C	t <sub>d(on)</sub>	_	146	_	ns
Rise Time	$V_{CE}$ = 600 V, $I_{C}$ = 150 A $V_{GE}$ = -8 V, 15 V, $R_{Gon}$ = 6 Ω,	t <sub>r</sub>	=	42	-	
Turn-off Delay Time	$R_{Goff} = 23 \Omega$	t <sub>d(off)</sub>	=	977	-	
Fall Time		t <sub>f</sub>	-	12	-	
Turn-on Switching Loss per Pulse		E <sub>on</sub>	-	7790	-	μJ
Turn-off Switching Loss per Pulse	1	E <sub>off</sub>	-	8530	-	
Input Capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>ies</sub>	_	26093	_	pF
Output Capacitance	1	C <sub>oes</sub>	_	1012	_	
Reverse Transfer Capacitance	1	C <sub>res</sub>	_	104	_	
Total Gate Charge	V <sub>CE</sub> = 600 V, I <sub>C</sub> = 300 A, V <sub>GE</sub> = 15 V	Qg	_	1304	-	nC
Thermal Resistance – Chip-to-Heatsink	Thermal grease, Thickness = 2.1 Mil ±2%	R <sub>thJH</sub>	=	0.207	=	K/W
Thermal Resistance - Chip-to-Case	$\lambda = 2.9 \text{ W/mK}$	R <sub>thJC</sub>	-	0.087	-	K/W
GBT INVERSE DIODE (D1, D2, D3, I	D4) CHARACTERISTICS			-		
Diode Forward Voltage	I <sub>F</sub> = 150 A, T <sub>J</sub> = 25°C	$V_{F}$	-	2.0	2.6	V
	I <sub>F</sub> = 150 A, T <sub>J</sub> = 150°C	<b> </b>	-	1.77	-	1
Reverse Recovery Time	T <sub>J</sub> = 25°C	t <sub>rr</sub>	=	105	-	ns
Reverse Recovery Charge	$V_{CE} = 600 \text{ V, } I_{C} = 150 \text{ A}$ $V_{GE} = -8 \text{ V, } 15 \text{ V, } R_{G} = 6 \Omega$	Q <sub>rr</sub>	_	4179	-	nC
Peak Reverse Recovery Current	- rae	I <sub>RRM</sub>	=	97	-	Α
Peak Rate of Fall of Recovery Current	]	di/dt	_	4571	_	A/μs
Reverse Recovery Energy	1	E <sub>rr</sub>	_	950	-	μJ
Reverse Recovery Time	T <sub>J</sub> = 125°C	t <sub>rr</sub>	_	179	-	ns
Reverse Recovery Charge	$V_{CE} = 600 \text{ V}, I_{C} = 150 \text{ A}$ $V_{GE} = -8 \text{ V}, 15 \text{ V}, R_{G} = 6 \Omega$	Q <sub>rr</sub>	_	11900	_	nC
Peak Reverse Recovery Current	ac - 1, 1-1, 11d - 1-1	I <sub>RRM</sub>	_	132	-	Α
Peak Rate of Fall of Recovery Current	1	di/dt	-	4167	_	A/μs
Reverse Recovery Energy		E <sub>rr</sub>	_	3750	-	μJ
Thermal Resistance – Chip-to-Heatsink	Thermal grease, Thickness = 2.1 Mil ±2%	R <sub>thJH</sub>	_	0.316	-	K/W
Thermal Resistance - Chip-to-Case	$\lambda = 2.9 \text{ W/mK}$	R <sub>thJC</sub>		0.197	_	K/W

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified) (continued)

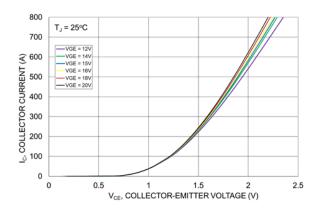
Characteristic	Characteristic Test Conditions		Min	Тур	Max	Unit
THERMISTOR CHARACTERISTICS						
Nominal Resistance	T = 25°C	R <sub>25</sub>	-	22	-	kΩ
Nominal Resistance	T = 100°C	R <sub>100</sub>	-	1486	-	Ω
Deviation of R25		ΔR/R	-5	-	5	%
Power Dissipation		P <sub>D</sub>	-	200	-	mW
Power Dissipation Constant			-	2	-	mW/K
B-value	B (25/50), tolerance ±3%		-	3950	-	K
B-value	B (25/100), tolerance ±3%		_	3998	_	K

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

### **ORDERING INFORMATION**

Part Number	Marking	Package	Shipping
NXH400N100H4Q2F2PG PRESS FIT PINS	NXH400N100H4Q2F2PG	PIM42, 93x47 (PRESSFIT) (Pb-Free/Halide-Free)	12 Units / Blister Tray
NXH400N100H4Q2F2SG, NXH400N100H4Q2F2SG-R SOLDER PINS	NXH400N100H4Q2F2SG, NXH400N100H4Q2F2SG-R	PIM44, 93x47 (SOLDER PIN) (Pb-Free/Halide-Free)	12 Units / Blister Tray

### TYPICAL CHARACTERISTICS - IGBT, INVERSE DIODE AND NEUTRAL POINT DIODE



800 T<sub>J</sub> = 150°C 700 -VGE = 12V 600 -VGE = 14V -VGE = 15V Ic, COLLECTOR CURRENT (A) VGE = 16V 500 -VGE = 18V -VGE = 20V 400 300 200 100 0 0 2.5 3.5 V<sub>CE</sub>, COLLECTOR-EMITTER VOLTAGE (V)

Figure 3. Typical Output Characteristics - Inner IGBT

Figure 4. Typical Output Characteristics - Inner IGBT

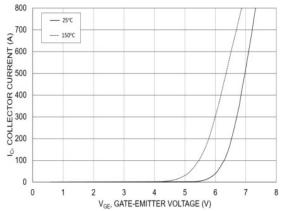


Figure 5. Transfer Characteristics – Inner IGBT

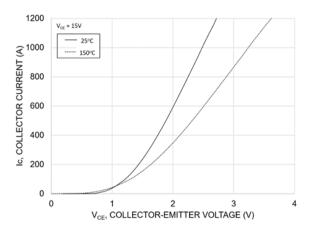


Figure 6. Saturation Voltage Characteristic

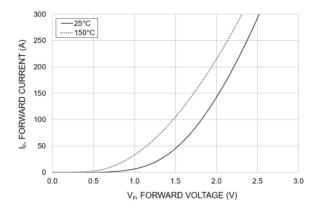


Figure 7. Inverse Diode Forward Characteristics

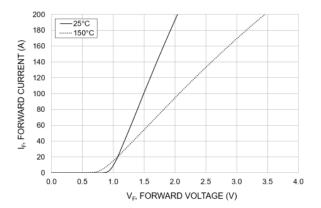


Figure 8. Buck Diode Forward Characteristics

#### **TYPICAL CHARACTERISTICS – OUTER IGBT**

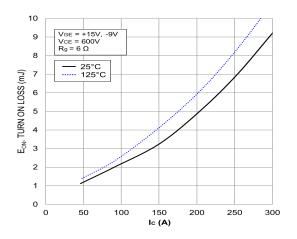


Figure 9. Typical Turn ON Loss vs. IC

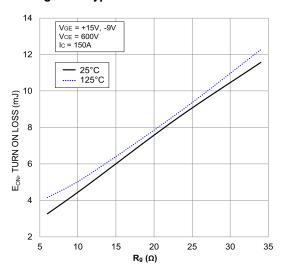


Figure 11. Typical Turn On Loss vs. Ra

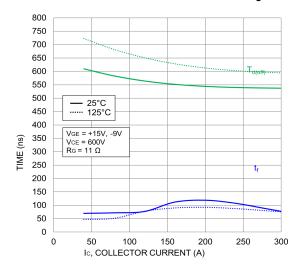


Figure 13. Typical Turn-Off Switching Time vs. IC

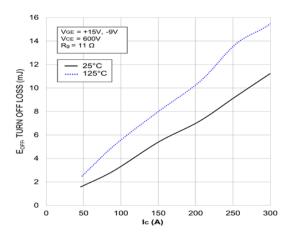


Figure 10. Typical Turn OFF Loss vs. IC

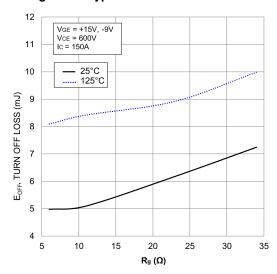


Figure 12. Typical Turn Off Loss vs. Rg

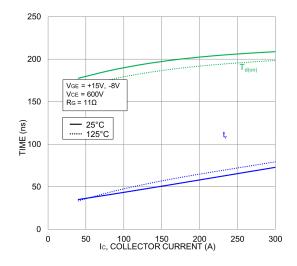
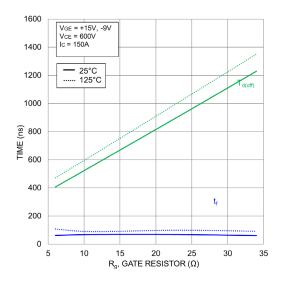


Figure 14. Typical Turn-On Switching Time vs. IC

## TYPICAL CHARACTERISTICS - OUTER IGBT (CONTINUED)



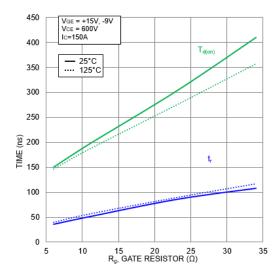


Figure 15. Typical Turn-Off Switching Time vs.  $R_{\rm g}$ 

Figure 16. Typical Turn-On Switching Time vs. Rq

### **TYPICAL CHARACTERISTICS – INNER IGBT**

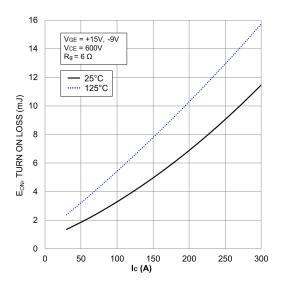


Figure 17. Typical Turn On Switching Time vs. I<sub>C</sub>

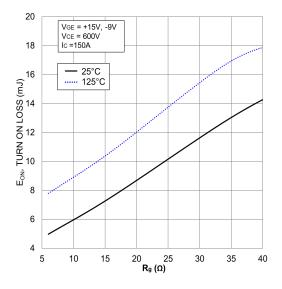


Figure 19. Typical Turn On Switching Time vs. R<sub>G</sub>

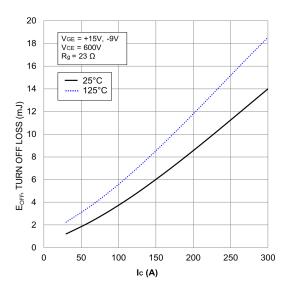


Figure 18. Typical Turn Off Switching Time vs. I<sub>C</sub>

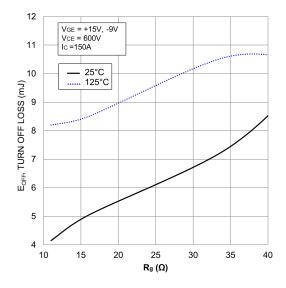


Figure 20. Typical Turn Off Switching Time vs. R<sub>G</sub>

### TYPICAL CHARACTERISTICS - INNER IGBT (CONTINUED)

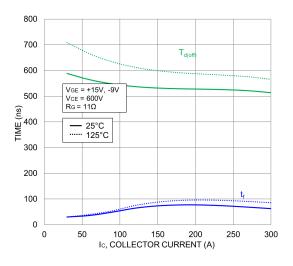


Figure 23. Typical Turn-Off Switching Time vs. I<sub>C</sub>

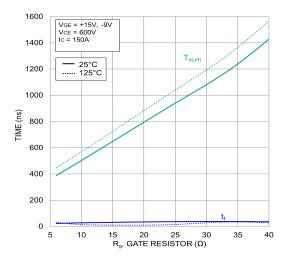


Figure 21. Typical Turn-Off Switching Time vs. Ra

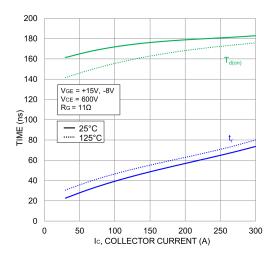


Figure 24. Typical Turn-On Switching Time vs.  $I_{\mathbb{C}}$ 

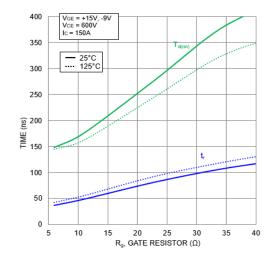


Figure 22. Typical Turn-On Switching Time  $vs.R_{\alpha}$ 

### TYPICAL SWITCHING CHARACTERISTICS - NEUTRAL POINT DIODE

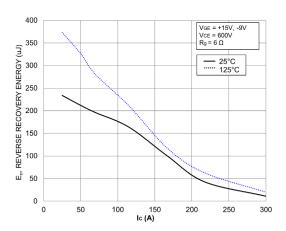


Figure 25. Typical Reverse Recovery Energy Loss vs. I<sub>C</sub>

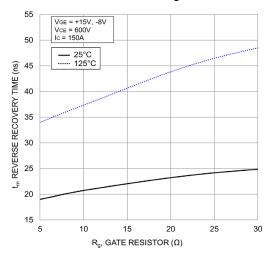


Figure 27. Typical Reverse Recovery Time vs. Rq

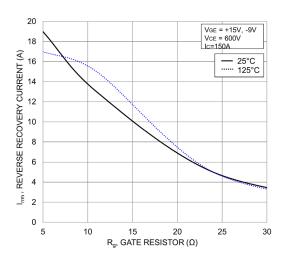


Figure 29. Typical Reverse Recovery Peak Current vs. R<sub>g</sub>

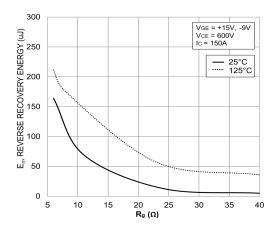


Figure 26. Typical Reverse Recovery Energy Loss vs.  $R_{\alpha}$ 

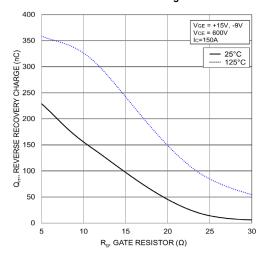


Figure 28. Typical Reverse Recovery Charge vs. Ra

#### TYPICAL CHARACTERISTICS - INVERSE DIODE

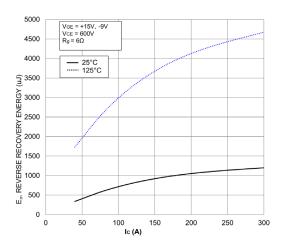


Figure 30. Typical Reverse Recovery Energy Loss vs. I<sub>C</sub>

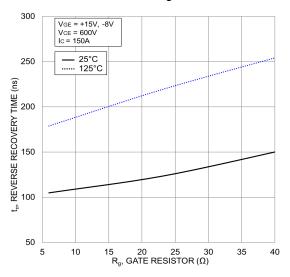


Figure 32. Typical Reverse Recovery Time vs. R<sub>a</sub>

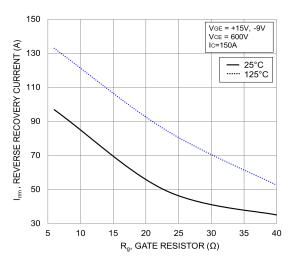


Figure 34. Typical Reverse Recovery Peak Current vs. R<sub>q</sub>

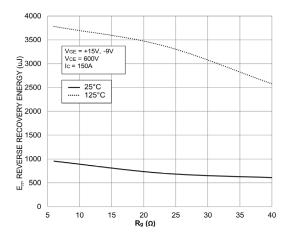


Figure 31. Typical Reverse Recovery Energy Loss vs. R<sub>g</sub>

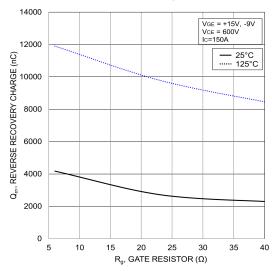


Figure 33. Typical Reverse Recovery Charge vs. Rg

### TYPICAL CHARACTERISTICS - IGBT, INVERSE DIODE AND NEUTRAL POINT DIODE

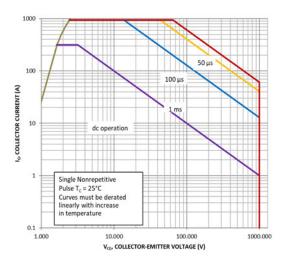


Figure 35. FBSOA - Outer IGBT

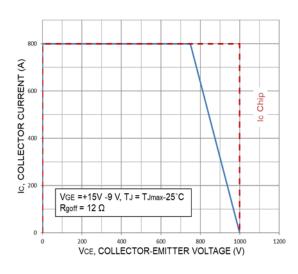


Figure 36. RBSOA - Outer IGBT

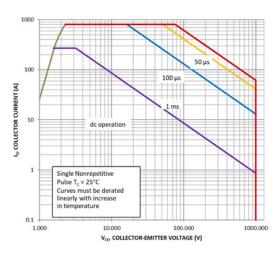


Figure 37. FBSOA - Inner IGBT

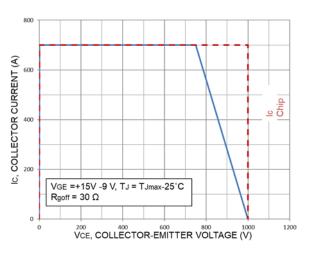


Figure 38. RBSOA - Inner IGBT

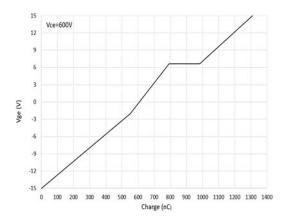


Figure 39. Gate Voltage vs. Gate Charge

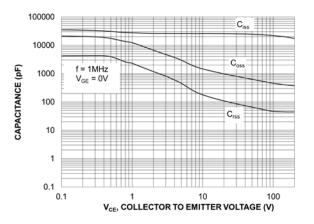


Figure 40. Capacitance Charge

## TYPICAL CHARACTERISTICS - IGBT, INVERSE DIODE AND NEUTRAL POINT DIODE (CONTINUED)

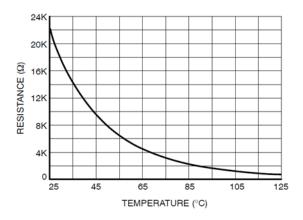


Figure 41. Thermistor Characteristics

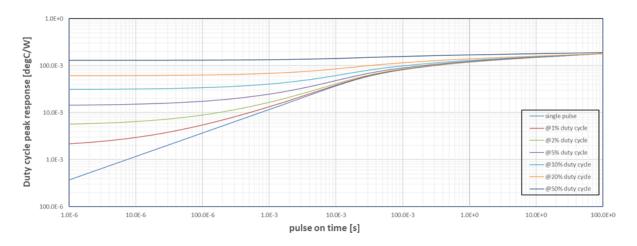


Figure 42. Transient Thermal Impedance - Outer IGBT

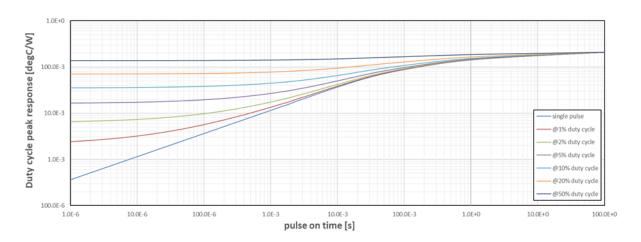


Figure 43. Transient Thermal Impedance – Inner IGBT

## TYPICAL CHARACTERISTICS - IGBT, INVERSE DIODE AND NEUTRAL POINT DIODE (CONTINUED)

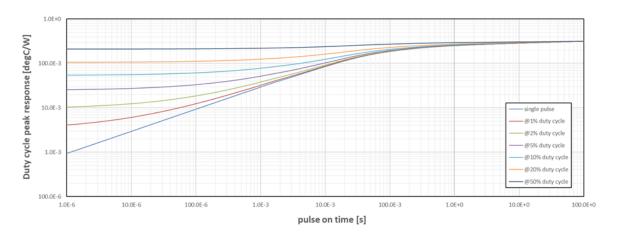


Figure 44. Transient Thermal Impedance – Inverse Diode

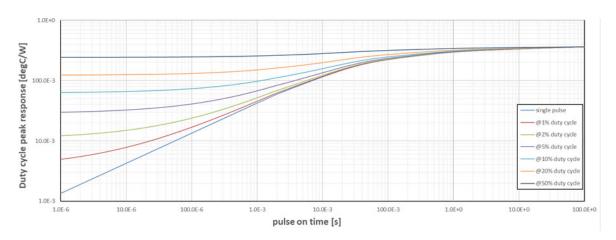
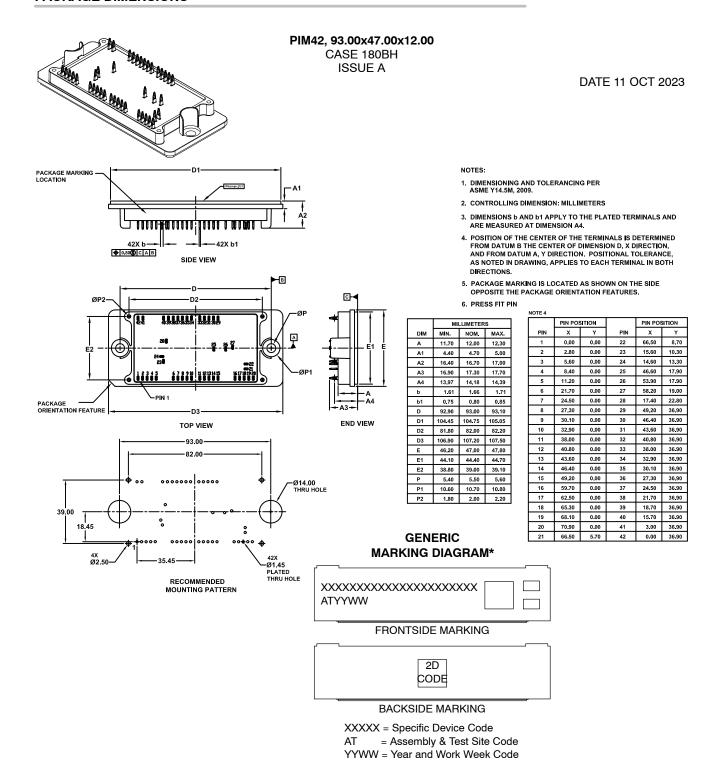


Figure 45. Transient Thermal Impedance – Neutral Point Diode



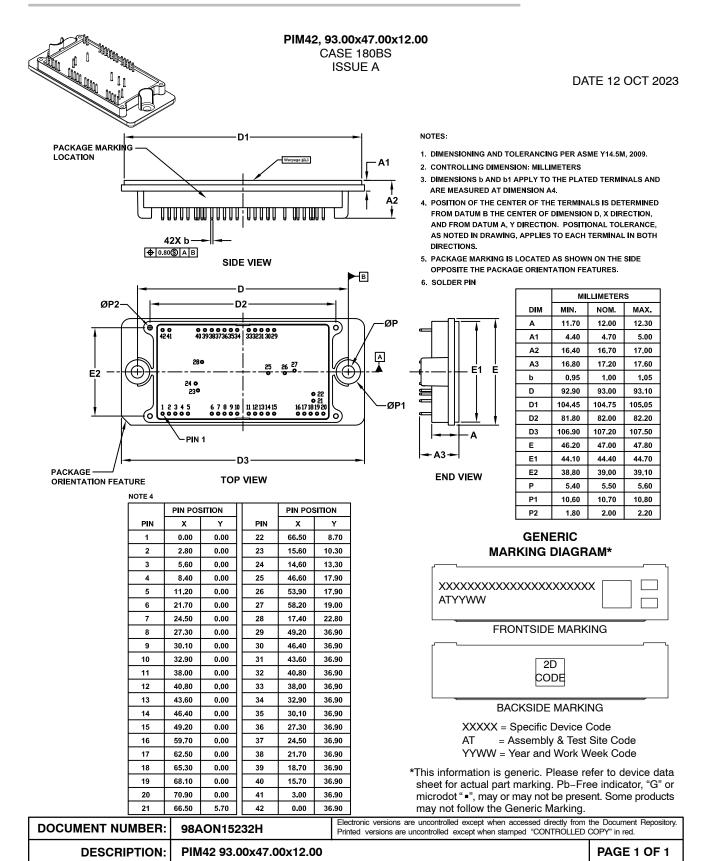


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